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L1	1719	imag\$4 same coordinat\$4 same sens\$4 same displa\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
L2	108	L1 same displac\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
L3	6341	displac\$4 near4 sens\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
L4	512	L3 same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
L5	217	(382/106).CCLS.	US-PGPUB; USPAT; USOCR; IBM_TDB	OR	OFF	2005/04/01 14:35
L6	512	L3 same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
L7	21	L6 same coordinat\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
L8	5	L7 same (during time while)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
S1	1548	imag\$4 same coordinat\$4 same sens\$4 same displa\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/09/14 14:05
S2	103	S1 same displac\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
S3	30	S2 same time	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/09/14 14:09
S4	6011	displac\$4 near4 sens\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/09/14 14:10
S5	481	S4 same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
S6	21	S5 same coordinat\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/09/14 14:10
S7	5	S6 same (during time while)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35

S8	192	(382/106).CCLS.	US-PGPUB; USPAT; USOCR; IBM_TDB	OR	OFF	2005/04/01 14:35
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IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

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